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TABLE OF CONTENTS

X-Masking for In-System Deterministic Test	1
<i>Grzegorz Mrugalski, Janusz Rajski, Jerzy Tyszer, Bartosz Wlodarczak</i>	
Reducing Routing Overhead by Self-Enabling Functional Path Ring Oscillators	7
<i>Tobias Kilian, Markus Hanel, Daniel Tille, Martin Huch, Ulf Schlichtmann</i>	
Research on Path Delay with BTI Recovery Effect	13
<i>Jiebing Wu, Yongsheng Sun, Yuan Wang, Yukai Lin, Mingna Fan, Junlin Huang</i>	
Evaluating Security of New Locking SIB-Based Architectures.....	17
<i>Yogendra Sao, Anjum Riaz, Satyadev Ahlawat, S. Subidh Ali</i>	
TaintLock: Preventing IP Theft Through Lightweight Dynamic Scan Encryption Using Taint Bits.....	23
<i>Jonti Talukdar, Arjun Chaudhuri, Krishnendu Chakrabarty</i>	
A Lightweight, Plug-And-Play and Autonomous JTAG Authentication IP for Secure Device Testing.....	29
<i>S. Lapeyre, N. Valette, M. Merandat, M.-L. Flottes, B. Rouzeyre, A. Virazel</i>	
A Data-Driven Approach for Fault Detection in the Alternator Unit of Automotive Systems.....	33
<i>Arunkumar Vijayan, Mehdi B. Tahoori, Ewald Kintzli, Timm Lohmann, Juergen Hans Handl</i>	
On Extracting Reliability Information from Speed Binning.....	37
<i>Zahra Paria Najafi-Haghi, Florian Klemme, Hussam Amrouch, Hans-Joachim Wunderlich</i>	
A Generic Fast and Low Cost BIST Solution for CMOS Image Sensors	41
<i>J. Lefevre, P. Debaud, P. Girard, A. Virazel</i>	
FPGA Design Deobfuscation by Iterative LUT Modifications at Bitstream Level.....	43
<i>Michail Moraitis, Elena Dubrova</i>	
Quality Assessment of RFET-Based Logic Locking Protection Mechanisms Using Formal Methods.....	45
<i>Marcel Merten, Sebastian Huhn, Rolf Drechsler</i>	
RRAM Crossbar-Based Fault-Tolerant Binary Neural Networks (BNNs).....	47
<i>Anteneh Gebregiorgis, Artemis Zografou, Said Hamdioui</i>	
Detection of Malicious FPGA Bitstreams Using CNN-Based Learning.....	49
<i>Jayeeta Chaudhuri, Krishnendu Chakrabarty</i>	
Hierarchical Memory Diagnosis.....	51
<i>G. C. Medeiros, M. Fieback, A. Gebregiorgis, M. Taouil, L. B. Poehls, S. Hamdioui</i>	
Novel Design for Test (DFT) Concept to Check the Spectral Mask Compliance Defined in the IEEE Std. 802.15.6-2012 of Wireless-Body-Area-Network (WBAN) IC-Devices.....	53
<i>Alexander Stephan Oleszczuk, Mohamed Thouabtia, Martin Allinger, Jurgen Rober, Robert Weigel</i>	
Graph Theory Approach for Multi-Site ATE Board Parameter Extraction.....	55
<i>Abraham Steenhoek, Praise O. Farayola, Isaac Bruce, Shravan Chaganti, Abalhassan Sheikh, Srivaths Ravi, Degang Chen</i>	

Prediction of Thermally Accelerated Aging Process at 28nm.....	57
<i>Parvez Anwar Chanawala, Ian Hill, S. Arash Sheikholeslam, Andre Ivanov</i>	
Machine Learning Based Soft Error Rate Estimation of Pass Transistor Logic in High-Speed Communication	59
<i>Z. Zhang, J. Lappas, A. Chinazzo, C. Weis, Z. Wu, L. Ni, N. Wehn, M. Tahoori</i>	
Super Acceleration of Dilithium in MPSoCs Critical Environments	63
<i>Johanna Sepulveda, Dominik Winkler</i>	
Real-Time Control-Flow Integrity for Multicore Mixed-Criticality IoT Systems.....	67
<i>Vahid Eftekhari Moghadam, Paolo Prinetto, Gianluca Roascio</i>	
Special Session on RF/5G Test: Challenges of 5G Production Test: RF and mmW Test Activities at CEA-Leti	71
<i>William R. Eisenstadt, Mark Roos, Devin Morris, Jose Luis Gonzalez-Jimenez, Christophe Mounet, Manuel J. Barragan, Gildas Leger, Florent Cilici, Estelle Lauga-Larroze, Salvador Mir, Sylvain Bourdel, M. Margalef-Rovira, I. Alaji, H. Ghanem, G. Ducournau, C. Gaquiere</i>	
Trojan Insertions of Fully Programmable Valve Arrays	74
<i>Nadun Sinhabahu, Jian-De Li, Katherine Shu-Min Li, Sying-Jyan Wang, Tsung-Yi Ho</i>	
Smart Redundancy Schemes for ANNs Against Fault Attacks	76
<i>Troya Cagil Koylu, Said Hamdioui, Mottaqiallah Taouil</i>	
A Novel Collaborative SSD Test Case Clustering Method Associating I/O Workload and Function Coverage.....	78
<i>Gyohun Jeong, Sangmin Kim, Hyelyun Kim, Sunghee Lee</i>	
Novel Method to Measure Common Mode Transient Immunity of Isolators	80
<i>Mohamed Thouabtia, Alexander Oleszczuk, Thomas Girg, Martin Allinger</i>	
On-Chip Training of Crosstalk Predictors to Fit Uncertainties	82
<i>Rezgar Sadeghi, Ehsan Akbari, Mohamad Ali Saber</i>	
On-Line Reliability Estimation of Ring Oscillator PUF.....	84
<i>Sergio Vinagrero Gutierrez, Giorgio Di Natale, Elena-Ioana Vatajelu</i>	
Concurrent Error Detection for LSTM Accelerators	86
<i>Nooshin Nosrati, Seyedeh Maryam Ghasemi, Mahboobe Sadeghipour Roodsari, Zainalabedin Navabi</i>	
Process and Runtime Variation Robustness for Spintronic-Based Neuromorphic Fabric	88
<i>Soyed Tuhin Ahmed, Mahta Mayahinia, Michael Hefenbrock, Christopher Munch, Mehdi B. Tahoori</i>	
Effective Techniques for Automatically Improving the Transition Delay Fault Coverage of Self-Test Libraries.....	90
<i>Riccardo Cantoro, Francesco Garau, Patrick Girard, Nima Kolahimahmoudi, Sandro Sartoni, Matteo Sonza Reorda, Arnaud Virazel</i>	
Test, Reliability and Functional Safety Trends for Automotive System-On-Chip	92
<i>F. Angione, D. Appello, J. Aribido, J. Athavale, N. Bellarmino, P. Bernardi, R. Cantoro, C. De Sio, T. Foscale, G. Gavarini, J. Guerrero, M. Huch, G. Iaria, T. Kilian, R. Mariani, R. Martone, A. Ruospo, E. Sanchez, U. Schlichtmann, G. Squillero, M. Sonza Reorda, L. Sterpone, V. Tancorre, R. Ugioli</i>	

Enabling Coverage-Based Verification in Chisel	102
<i>Andrew Dobis, Hans Jakob Damsgaard, Enrico Tolotto, Kasper Hesse, Tjark Petersen, Martin Schoeberl</i>	
SpinalFuzz: Coverage-Guided Fuzzing for SpinalHDL Designs	108
<i>Katharina Ruep, Daniel Grobe</i>	
Memristor-Based Security Primitives	112
<i>Sergio Vinagrero Gutierrez</i>	
WLAN Rx PER Test Implementation in ATE	114
<i>Alban Haynse Immanuel, Jeyendran Nithyanadam</i>	
AMS Test Vector Generation Using AMS Verification and IEEE P1687.2	118
<i>Vladimir A. Zivkovic, Michele Palazzi, Ming Chuen Alvan Lam, Mogens Isager</i>	
Impact of Atmospheric and Space Radiation on Sensitive Electronic Devices	122
<i>Lucas Matana Luza, Frederic Wrobel, Luis Entrena, Luigi Dilillo</i>	
CNN-Based Data-Model Co-Design for Efficient Test-Termination Prediction	132
<i>Hongfei Wang, Zhanfei Wu, Wei Liu</i>	
Optimized Diagnostic Strategy for Embedded Memories of Automotive Systems-On-Chip	138
<i>P. Bernardi, G. Insinga, G. Paganini, R. Cantoro, P. Beer, M. Coppetta, N. Mautone, G. Carnevale, P. Scaramuzza, R. Ullmann</i>	
An Optimized Burn-In Stress Flow Targeting Interconnections Logic to Embedded Memories in Automotive Systems-On-Chip	144
<i>F. Angione, P. Bernardi, G. Filipponi, M. Sonza Reorda, D. Appello, V. Tancorre, R. Ugioli</i>	
Machine Learning for Test, Diagnosis, Post-Silicon Validation and Yield Optimization	150
<i>Hussam Amrouch, Krishnendu Chakrabarty, Dirk Pfluger, Ilia Polian, Matthias Sauer, Matteo Sonza Reorda</i>	
On the Impact of Hardware Timing Errors on Stochastic Computing Based Neural Networks	156
<i>Florian Neugebauer, Stefan Holst, Ilia Polian</i>	
PVT Analysis for RRAM and STT-MRAM-Based Logic Computation-In-Memory	162
<i>Moritz Fieback, Christopher Munch, Anteneh Gebregiorgis, Guilherme Cardoso Medeiros, Mottaqiallah Taouil, Said Hamdioui, Mehdi Tahoori</i>	

ADDITIONAL PAPERS

Feature Selection Techniques for Indirect Test and Statistical Calibration of Mm-Wave Integrated Circuits	168
<i>Manuel J. Barragan, Gildas Leger, Florent Cilici, Estelle Lauga-Larroze, Salvador Mir, Sylvain Bourdel</i>	
Integrated Characterization Solutions for ICs and Devices Beyond 100 GHz	171
<i>M. Margalef-Rovira, I. Alaji, H. Ghanem, G. Ducournau, C. Gaquiere</i>	

Author Index